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Cheng

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(54) **STRUCTURE AND METHOD OF DATA SYNCHRONIZATION FOR MULTI MEASURING APPARATUS**

USPC 702/189; 370/320, 318, 317, 335; 324/713

See application file for complete search history.

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(*) Notice: Subject to any disclaimer, the term of this patent is extended or adjusted under 35 U.S.C. 154(b) by 470 days.

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(57) **ABSTRACT**

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In a structure and a method of data synchronization for multi measuring apparatuses, the multi measuring apparatuses link together to expand channels. One of those apparatuses is a master control measuring apparatus, and others are slave measuring apparatus. The master measuring apparatus can output synchronous signal to the slave measuring apparatuses. The slave measuring apparatus can retrieve the synchronous signal as a mark of data synchronization, and the synchronous signal and the marks are further stored in a memory. All the data and marks stored in the memory of the measuring apparatuses are transferred to a processing platform. By the software installed in the processing platform, the data wave form length of the master control measuring apparatus and slave measuring apparatus can be adjusted to the same, and the problem caused by the clock error of the measuring apparatus can be solved as well.

(58) **Field of Classification Search**

CPC G01R 31/31726; G01R 13/0254; G01R 13/0218; G01R 31/31922; G01R 31/31937; G01R 13/342; G05B 19/0426; G05B 2219/23446; H04B 7/022; H04B 17/1117; H04B 2201/70701; H04B 17/006; H04L 7/0012

12 Claims, 7 Drawing Sheets

